エミッション測定法　IEC 61967シリーズ

◆IEC 61967: Integrated circuits, Measurement of Electromagnetic emission

ドキュメント	メカニズム	測定法	ステータス
IEC 61967 シリーズ	-	Part1 General conditions and definitions	IS, Ed.2, 2018
		Part1-1 Near-field scan data exchange format	TR, Ed.2, 2015
	Conducted **E**mission	Part4 1Ω/150Ω direct coupling	IS, Ed.1.1, 2006 <Ed.2 CD審議開始, 2019～>
		Part4-1 Application guidance to IEC 61967-4	TR, 2005
		Part5 WBFC(Workbench Faraday Cage)	IS, 2003
		Part6 Magnetic probe	IS, Ed.1.1, 2008
	Radiated **E**mission	Part2 TEM-cell and wideband TEM-cell	IS, 2005
		Part3 Surface scan	TS, Ed.2, 2014
		Part8 IC strip line	IS, 2011

IS: International Standard (国際規格)
TS: Technical Specification (技術仕様書)
TR: Technical Report (技術報告書)

Copyright (C) 2018 JEITA Semiconductor EMC-SC All Rights Reserved.

イミュニティ測定法　IEC 62132/62215シリーズ

◆ IEC 62132:　Integrated circuits, Measurement of Electromagnetic Immunity

ドキュメント	メカニズム	測定法	ステータス
IEC 62132 シリーズ	-	Part1 General conditions and definitions	IS, Ed.2, 2015
	Conducted **I**mmunity	Part3 BCI(Bulk Current Injection)	IS, 2007
		Part4 DPI(Direct RF power injection)	IS, Ed.1, 2006 <Ed.2改訂予定>
		Part5 WBFC(Workbench Faraday Cage)	IS, 2005
	Radiated **I**mmunity	Part2 TEM-cell and wideband TEM-cell	IS, 2010
		Part8 IC strip line	IS, 2012
		Part9 Surface scan	TS, 2014

◆ IEC 62215:　Integrated circuits, Measurement of impulse immunity

ドキュメント	メカニズム	測定法	ステータス
IEC 62215 シリーズ	Impulse immunity	Part2 Synchronous transient injection	TS, 2007
		Part3 Non-synchronous transient injection	IS, 2013

IS: International Standard (国際規格)
TS: Technical Specification (技術仕様書)

Copyright (C) 2018 JEITA Semiconductor EMC-SC All Rights Reserved.

バス・トランシーバ測定法　IEC 62228シリーズ

◆ IEC 62228: EMC evaluation of bus transceivers

ドキュメント	メカニズム	測定法	ステータス
IEC 62228 シリーズ	-	Part1 General conditions and definitions	IS, Ed.1, 2018
	Evaluation of bus transceivers	Part2 LIN transceivers	IS, Ed.1, 2016
		CAN transceivers	TS, 2007　Part3に移行
		Part3 CAN(FD) transceivers	IS, Ed.1 2019
		Part4 FlexRay transceivers	WD <DE提案予定, 未定>
		Part5 Ethernet transceivers	CD <CD審議中, 2019～>
		Part6 PSI5 transceivers	WD <IE提案予定, 2019～>
		Part7 CXPI transceivers	CD <CD審議予定, 2019～>
		Part8 SENT/SPC transceivers	T.B.D.
		Part9 LVDS transceivers	T.B.D.

IS: International Standard (国際規格)、 TS: Technical Specification (技術仕様書)、
FDIS: Final Draft International Standard (最終国際規格案)、 CD: Committee Draft(委員会原案)、
NP: New work item Proposal (新業務項目提案)、 WD: Working Draft (作業原案)

Copyright (C) 2018 JEITA Semiconductor EMC-SC All Rights Reserved.

ICのEMCモデリング手法　IEC 62433シリーズ

◆ IEC 62433シリーズ:　EMC IC modelling,

ドキュメント	メカニズム	モデリング法	ステータス
IEC 62433 シリーズ	-	Part1 General modelling framework	IS　Ed.1, 2019
	Conducted **E**mission	Part2 Models of Integrated circuits for EMI behavioural simulation -Conducted emissions modelling (ICEM-CE)	IS, Ed.2, 2017
		Part2-1 Theory of black box modelling for conducted emission	TR, 2010
	Radiated **E**mission	Part3 Models of Integrated circuits for EMI behavioural simulation -Radiated emissions modelling (ICEM-RE)	IS, Ed.1, 2017
	Conducted **I**mmunity	Part4 Models of Integrated circuits for RF Immunity behavioural simulation -Conducted immunity modelling (ICIM-CI)	IS, Ed.1, 2016
	Radiated **I**mmunity	Part5 -----(ICIM-RI)	T.B.D.
	Pulse **I**mmunity	Part6 Models of Integrated circuits for immunity behavioural simulation -Conducted pulse immunity modelling(ICIM-CPI)	CD＜4thCD 審議終了, 2019～＞

標準化メリット　・モデル要件、フォーマットに関する仕様整合の時間省
・シミュレーションを活用したEMC設計のサポート

IS
FD　　原案)、
NP

Copyright (C) 2018 JEITA Semiconductor EMC-SC All Rights Reserved.